

Near-Field Current Tomography for Spatially Resolved Emission Diagnostics in Multi-Emitter Electro spray Arrays

Maurizio Saggiani, Mick Wijnen, Jaume Navarro Cavallé
IENAI SPACE / Universidad Carlos III de Madrid

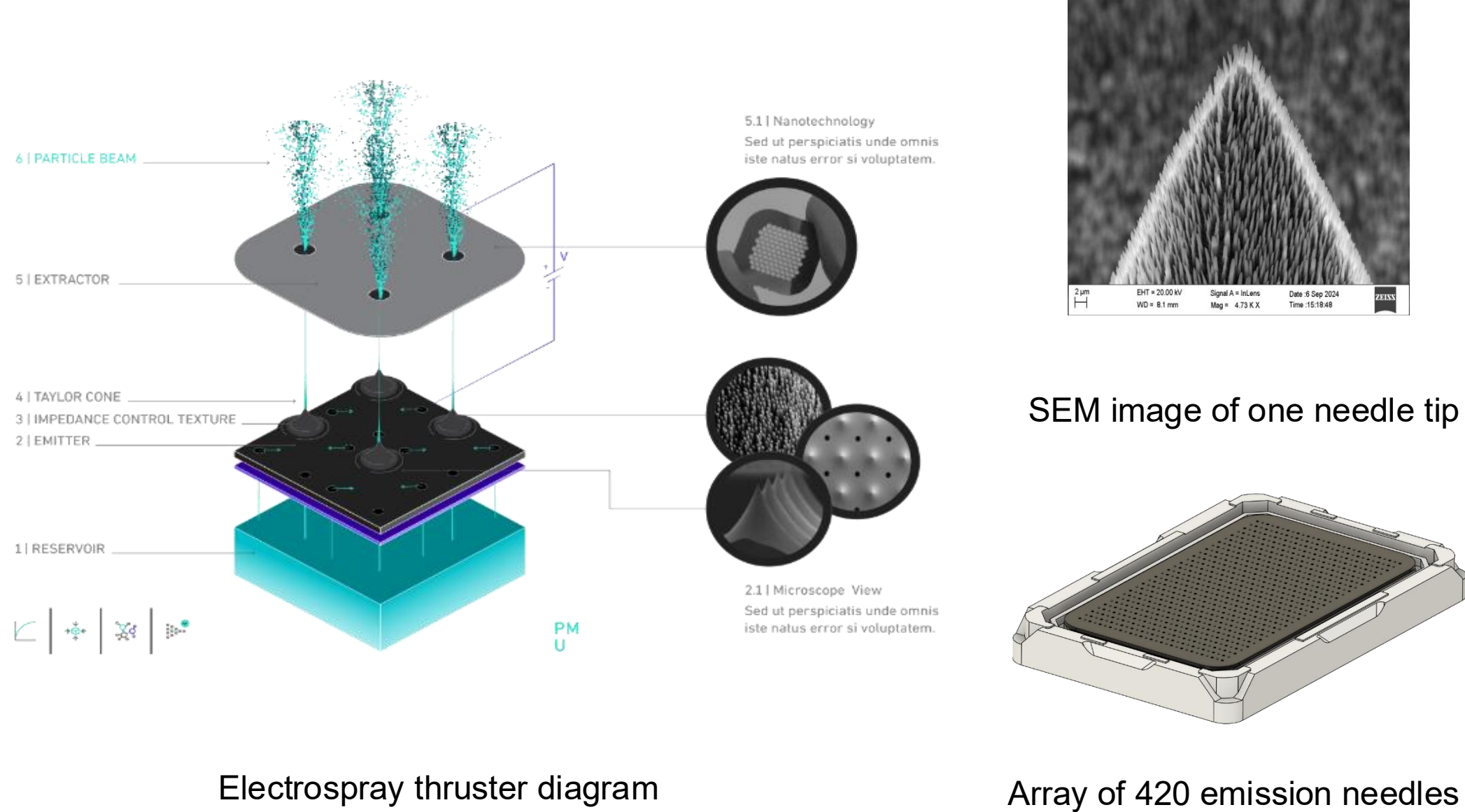
Motivation

Electrospray thrusters operate as distributed emission systems in which hundreds of emitters contribute simultaneously to total beam current. In an ideal array, each emitter operates under identical electrostatic and geometric conditions. In practice, manufacturing tolerances, bonding-induced misalignments, and local wetting variability introduce emitter-to-emitter differences that produce substantial spatial non-uniformity in current density.

Thrusters are commonly qualified using bulk electrical measurements: total emitted beam current, which represent only the spatial integral of the emission distribution. Fundamentally different emission states (uniform vs. clustered) can produce indistinguishable total current values. Classical diagnostics are therefore intrinsically blind to spatial emission structure.

Direct performance consequences: localised over-emission increases accelerates degradation; under-utilised regions reduce effective array efficiency; asymmetric emission induces plume misalignment and premature failure — even when total current remains nominal.

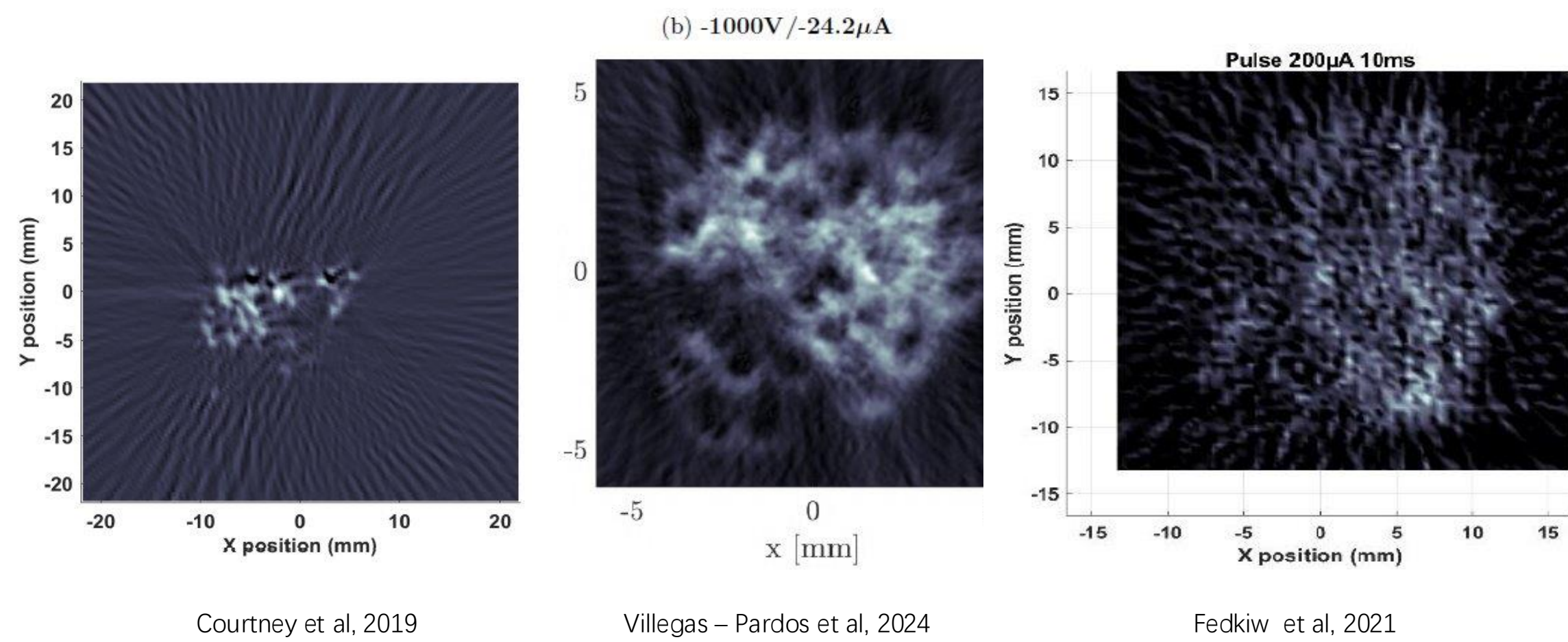
→ **A diagnostic capable of resolving the spatial distribution of emitted current is required to bridge the gap between local emission physics and global thruster behaviour.**



State of the Art

Near-field current tomography (CT) uses wire-probe line-integrated current measurements to reconstruct the 2D current density distribution $J(x,y)$ across the array via filtered backprojection (Fourier Slice Theorem).

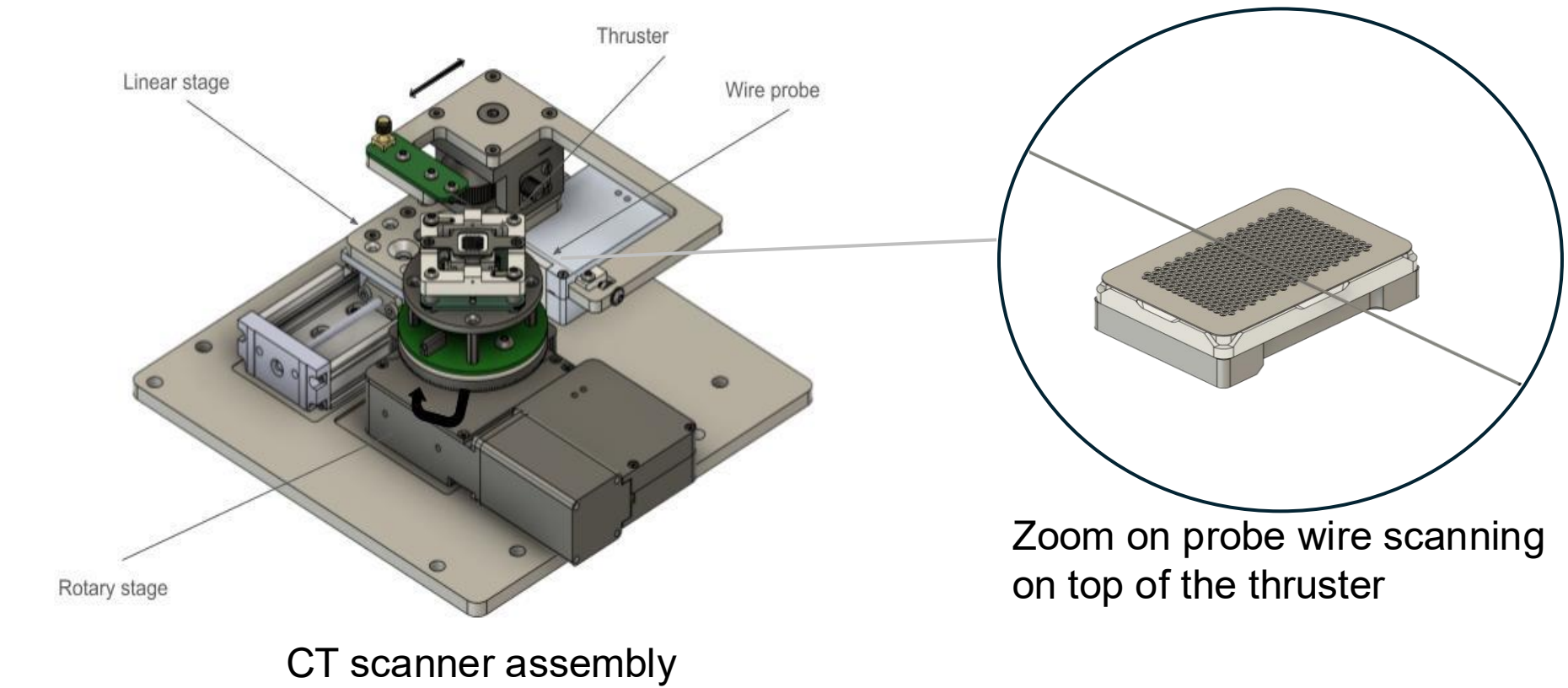
Prior work: Courtney et al. (2019) established the CT geometric framework; Fedkiw et al. (2021) refined current mapping techniques; Villegas-Prados et al. (2024) extended CT to externally wetted architectures. These demonstrated qualitative capability to reveal non-uniformity.



Unresolved limitations: (1) Angular undersampling, no enforcement of the Nyquist sampling theorem applied to 2D periphery of the Fourier Space. (2) No quantitative validation — prior studies present CT maps without demonstrating that spatially integrated current recovers the independently measured I–V data. (3) No single emission site resolution.

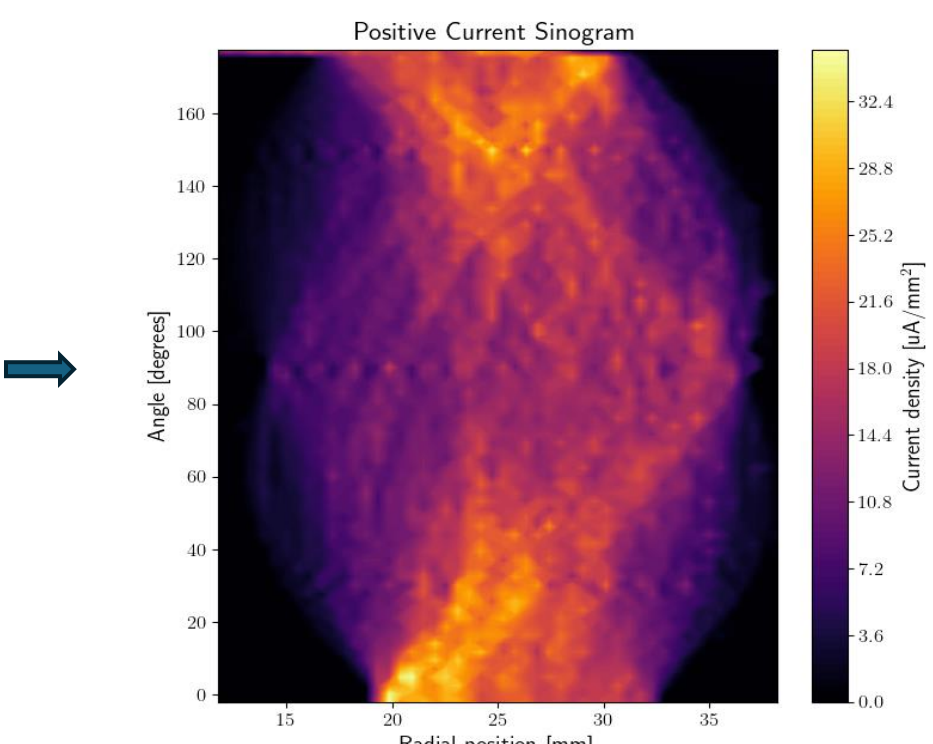
Objectives

- Enforce Nyquist-consistent sampling in CT reconstruction through projection-space radial binning, suppressing frequency-domain artifacts prior to filtered backprojection.
- Resolving singular emission sites enforcing that the reconstruction pixel size is smaller than the needles interspacing area
- Establish quantitative validation by demonstrating conservation of total emitted current: integrated CT current must close against independently measured I–V data.
- Characterise emission non-uniformity in a 420-needle silicon array using CT, profilometry, and 2D electrostatic simulation, linking assembly geometry to spatial emission topology.



Methodology

For each angular position, the probe performs a linear sweep across the beam, recording the intercepted current. The collection of line-integrated measurements forms a **sinogram** $p(r, \theta)$.

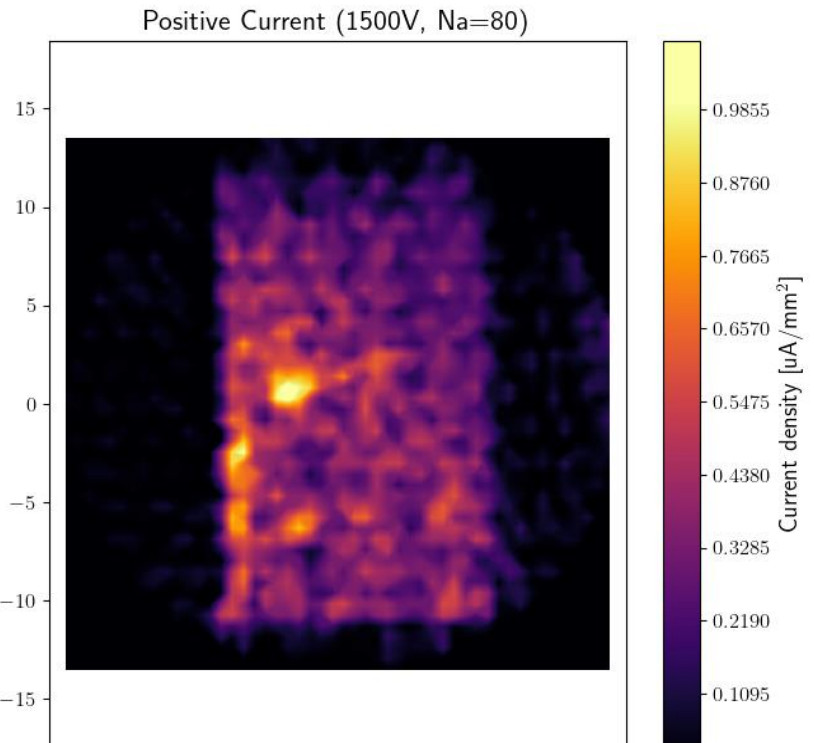


Filtered Backprojection is the dominant reconstruction algorithm for CT. It reconstructs an object function $f(x,y)$ from the set of its line-integral projections $p(r, \theta)$ by filtering each projection with a ramp-shaped frequency filter and then backprojecting the result over the image plane. FBP falls directly out of rewriting the 2D inverse Fourier transform in polar coordinates (r, θ)

$$j(x,y) = \int_0^\pi Q_\theta(x \cos \theta + y \sin \theta) d\theta \quad \text{Where } Q_\theta \text{ is the FBP}$$

Where the ω factor is the ramp filter

$$Q_\theta(t) = \int_{-\infty}^{+\infty} \mathcal{F}\{I(\cdot, \theta)\}(\omega) |\omega| e^{j2\pi\omega t} d\omega$$



Frequency artifacts suppression and Single cone resolution

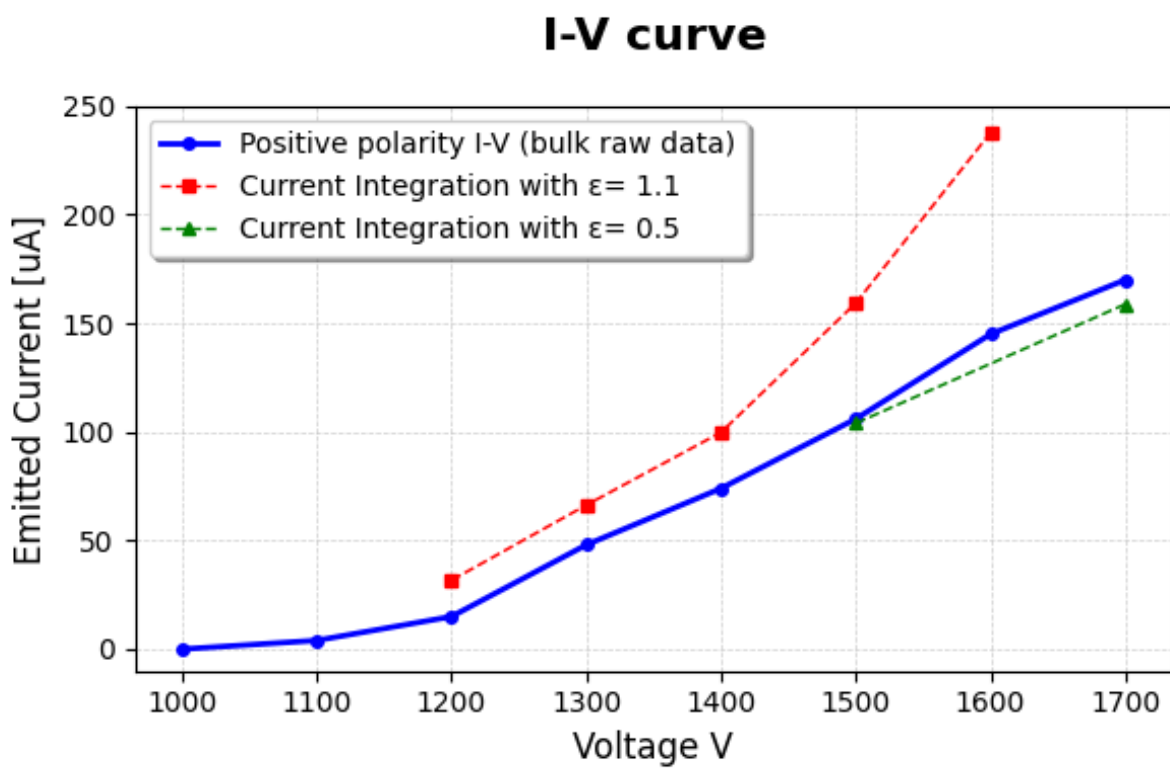
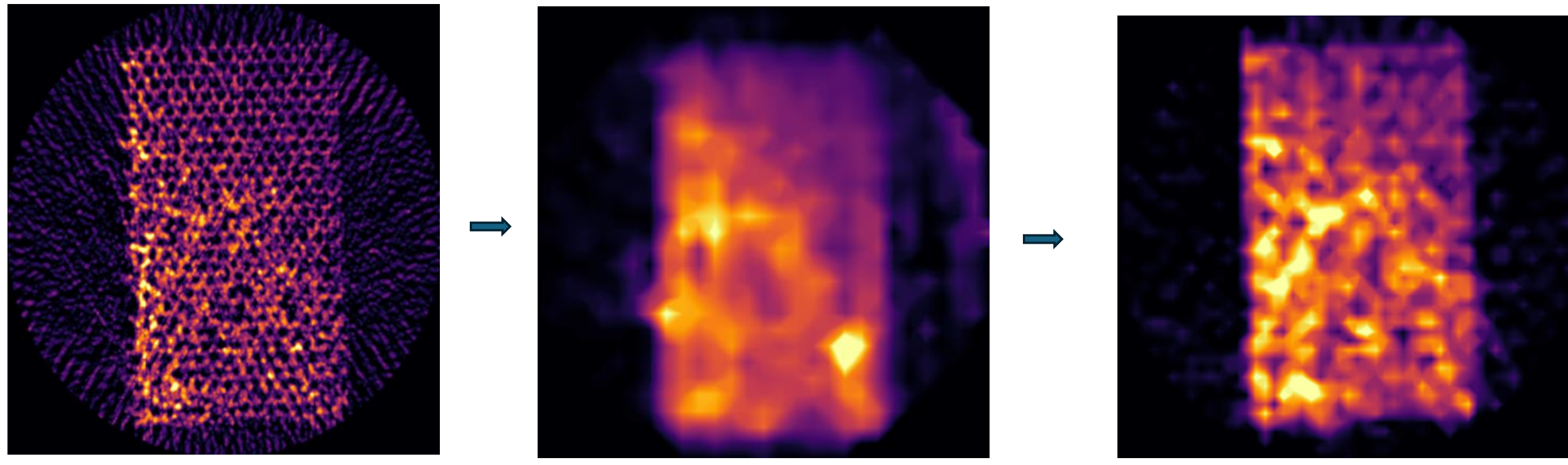
The sinogram is sampled in Fourier Space with the Radial frequency N_r and the Angular frequency N_θ . In order to not encounter frequency resonances in the reconstruction of the image, we need to enforce the Nyquist sampling theorem adapted to 2D coupled variables and enforced at the periphery of the Fourier Space : $N_\theta > (\pi/2) \cdot N_r$

To resolve single emission sites we had to enforce that the reconstruction pixel is smaller than the inter-needle spacing area : $\epsilon = n_{\text{needle}} \cdot A_{px} < 1$, where n_{needle} is the emission site spatial density and A_{px} the reconstruction pixel area

Quantitative validation – Integration Analysis

Integrating the current density $J(i,j)$ over the entire array we were able to cross check total emitted current with the bulk classical collective data: when $\epsilon < 1$ (no artifacts, single cone resolution) the predicted current match the bulk data with 1% error

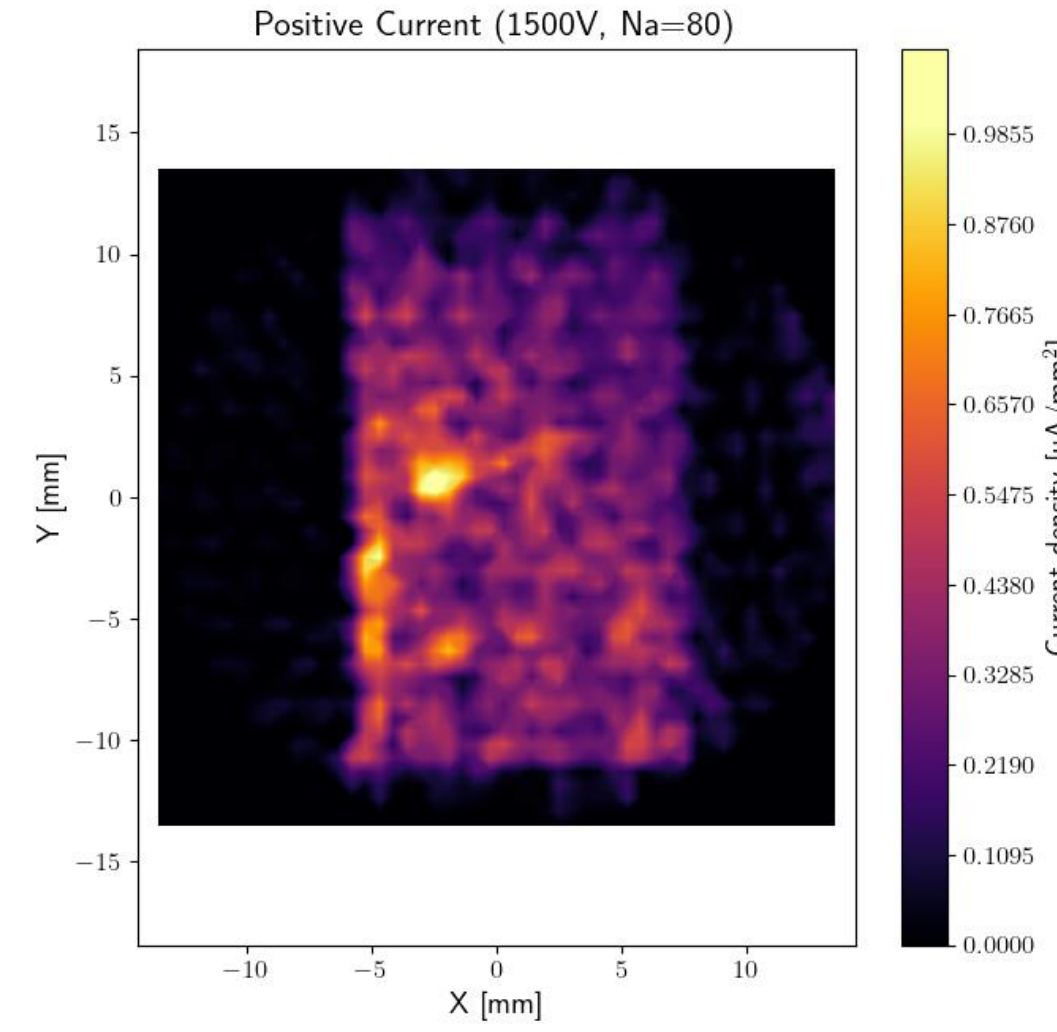
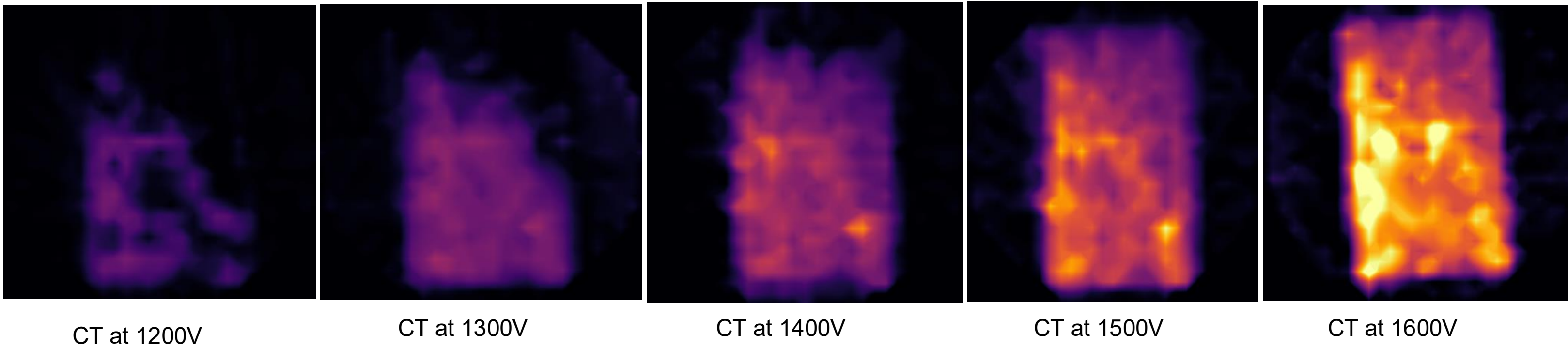
$$I_{CT} = \sum_{i,j}^{n_{px}} J_{i,j} A_{px}$$



Preliminary Research/Results

Emission Heterogeneity

The reconstructed emission maps reveal two distinct classes of spatial heterogeneity: first a **distributed non-uniformity** component arising from emitter-to-emitter geometric and surface variability. Hotspots with 4x the average emission per site are now identified as clear lifetime and performance bottleneck. Secondly a systematic **large-scale gradient** persisting across all operating voltages indicating a macroscopic geometric or electrostatic driver, rather than stochastic manufacturing dispersion.



Distributed local hot spots and non uniformities.

Electrostatic Closure

With the aid of a 3D optical profilometry we found that the emitter array and the extractor plane (ideally parallel planes with a design gap $g_0 = 150 \mu m$) had a relative inclination of 0.1° per axis. The distribution of the gap (g) with the planes inclination was plotted over the entire array area. A 2D COMSOL finite element model electrostatic simulation of a cone-extractor, to compute the needle tip electric field in function of g, allowed us to predict the current density distribution $J(x,y)$ in this scenario. Correlation with the CT image at the same voltage showed good correlation: The large scale gradient is due to a 0.1° plane non-complanarity of emitter and extractor planes. The distributed non uniformity due to emitter to emitter variability will be subject of further studies.

